## Application/Control No. Applicant(s)/Patent Under Reexamination LIN ET AL. Examiner Jack Chiang Application/Control No. Applicant(s)/Patent Under Reexamination LIN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-6,628,925	09-2003	Ishida et al.	455/73
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## **NON-PATENT DOCUMENTS**

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